RAM Mounts Testing Summary

RAM® Locking Modular Dock for Samsung Tab Active5 & 3

Products Covered

RAM-101-B-SAM58PKLH-V7B1-NFCU
RAM-101-B2-SAM58PKLH-V7B1-NFCU
RAM-HOL-SAM58CPKLN-CAU
RAM-HOL-SAM58PD2KLNU
RAM-HOL-SAM58PDKLHU
RAM-HOL-SAM58PDKLNU
RAM-HOL-SAM58PKL-NFCU
RAM-HOL-SAM58PKLH-V7B1U
RAM-HOL-SAM58PKLHU
RAM-HOL-SAM58PKLNU

Accompanying Power Supplies

RAM-GDS-CHARGE-V7B1U

Test	Description
Vibration – operational	MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
Functional Shock - operational	MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth.
Pogo Pins – Cycle rating	Pogo pins rated to 100k cycles
USB Validation Protocol, Speed, Power	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
Power Supply Input Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
Power Supply Output Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Power Supply Load Test	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Regulatory Compliance	FCC, IC CE, RoHS, WEEE
Safety, Emission, Immunity (Ram Power Supply)	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark

Official NPI testing documentation. Tests performed onsite by NPI engineers.